

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10769930	CHUNG ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	ALI BAYAT	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	100,115,119,121-122,187,219,305	2/26/08	A.B
348	161	2/26/08	A.B
345	179	2/26/08	A.B
73	865.4	2/26/08	S.B
178	18.01	2*26/08	A.B
	updated above	6/19/08	A.B

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST( US-PGPUB; USPAT; EPO; JPO; DERWENT; USOCR; FPRS), Inventor name searched, see text search history print out.	2/26/08	A.B
updated above plus IEEE EXPLORE DATABASE searched.	6/19/08	A.B

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
US-PGPUB	see Interference search history print out.	2/26/08	A.B
	updated above	6/19/08	A.B